We Claim:

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A semiconductor structure comprising: 1.

a monocrystalline silicon substrate;

an amorphous oxide material overlying the monocrystalline silicon substrate; a monocrystalline perovskite oxide material overlying the amorphous oxide material;

a monocrystalline compound semiconductor material overlying the monocrystalline perovskite oxide material; and

an optical processing layer overlying the monocrystalline compound 10 semiconductor material.

- The semiconductor structure of claim 1 wherein the optical processing layer is a 2. passive layer.
- The semiconductor structure of claim 1 wherein the optical processing layer is selected from the group consisting of a micro-Fresnel lens, a hologram lens, a grating 3. lens, a filter, a diffusion layer, a polarizer, a collimator, and a zone plate in combination with an objective lens.
- The semiconductor structure of claim 1 wherein the optical processing layer is a 4. active layer responsive to an active layer control signal.
- The semiconductor structure of claim 1 wherein the optical processing layer is selected from the group consisting of an electro-optic element, an electronically switchable Bragg grating (ESBG), a switchable hologram, a switchable diffraction 25 grating, a switchable collimator, an application specific optical element (ASOE), a switchable refractive element, and a liquid crystal array.

PATENT JG00389 56 The semiconductor structure of claim 1 wherein the optical processing layer is a 6. semi-active layer. The semiconductor structure of claim 1 wherein the optical processing layer is a 7. 5 photo luminescent layer. The semiconductor structure of claim 1 wherein the optical processing layer further comprises a plurality of optical processing sub-layers. 8. The semiconductor structure of claim 1 wherein the optical processing layer 10 9. further comprises a feedback sensor. The semiconductor structure of claim 1 wherein the monocrystalline compound semiconductor material further comprises a monocrystalline compound semiconductor 15 material having a plurality of lasers to produce photons. The semiconductor structure of claim 10 wherein optical processing layer further comprises an optical processing layer having a high beam state for collimating the photons and a low beam state for redirecting and diffusing the photons. 20 The semiconductor structure of claim 10 wherein the plurality of lasers further comprises a first laser group and a second laser group, the first laser group synchronized with the second laser group; and wherein the optical processing layer further comprises a first electro-optic element, the first electro-optic element optically connected to the 25 first laser group.

- 13. The semiconductor structure of claim 12 wherein the optical processing layer further comprises a second electro-optic element, the second electro-optic element optically connected to the second laser group.
- 5 14. A process for fabricating a semiconductor structure comprising:

 providing a monocrystalline silicon substrate;

 depositing a monocrystalline perovskite oxide film overlying the

 monocrystalline silicon substrate, the film having a thickness less than a thickness of
 the material that would result in strain-induced defects;
- forming an amorphous oxide interface layer at an interface between the monocrystalline perovskite oxide film and the monocrystalline silicon substrate; epitaxially forming a monocrystalline compound semiconductor layer overlying the monocrystalline perovskite oxide film; and

forming an optical processing layer overlying the monocrystalline compound semiconductor layer.

- 15. The process of claim 15 wherein forming an optical processing layer further comprises film laminating the optical processing layer over the monocrystalline compound semiconductor layer.
- 16. The process of claim 15 wherein forming an optical processing layer further comprises printing the optical processing layer over the monocrystalline compound semiconductor layer.
- 25 17. The process of claim 15 wherein forming an optical processing layer further comprises spin coating the optical processing layer over the monocrystalline compound semiconductor layer

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